

**N - CHANNEL ENHANCEMENT MODE  
POWER MOS TRANSISTOR**

TYPE	V <sub>DS</sub>	R <sub>D(on)</sub>	I <sub>D</sub>
BUZ41A	500 V	1.5 Ω	4.5 A

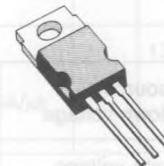
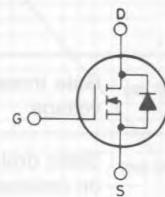
- HIGH VOLTAGE - FOR OFF-LINE SMPS
- ULTRA FAST SWITCHING FOR OPERATION AT < 100KHz
- EASY DRIVE - FOR REDUCED COST AND COST

**INDUSTRIAL APPLICATIONS:**

- SWITCHING POWER SUPPLIES
- MOTOR CONTROLS

N - channel enhancement mode POWER MOS field effect transistor. Easy drive and very fast switching times make this POWER MOS transistor ideal for high speed switching applications.

Typical applications include switching power supplies and motor speed control.


**TO-220**
**INTERNAL SCHEMATIC  
DIAGRAM**

**ABSOLUTE MAXIMUM RATINGS**

V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	500	V
V <sub>DGR</sub>	Drain-gate voltage (R <sub>GS</sub> = 20 KΩ)	500	V
V <sub>GS</sub>	Gate-source voltage	± 20	V
I <sub>D</sub>	Drain current (continuous) T <sub>c</sub> = 35°C	4.5	A
I <sub>DM</sub>	Drain current (pulsed)	18	A
P <sub>tot</sub>	Total dissipation at T <sub>c</sub> < 25°C	75	W
T <sub>stg</sub>	Storage temperature	- 55 to 150	°C
T <sub>j</sub>	Max. operating junction temperature	150	°C
	DIN humidity category (DIN 40040)	E	
	IEC climatic category (DIN IEC 68-1)	55/150/56	

## THERMAL DATA

$R_{thj}$ - case	Thermal resistance junction-case	max	1.67	$^{\circ}\text{C}/\text{W}$
$R_{thj}$ - amb	Thermal resistance junction-ambient	max	75	$^{\circ}\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ( $T_j = 25^{\circ}\text{C}$  unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
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## OFF

$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 250 \mu\text{A}$	$V_{GS} = 0$	500			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max Rating}$	$V_{DS} = \text{Max Rating}$	$T_j = 125^{\circ}\text{C}$		250 1000	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20 \text{ V}$				$\pm 100$	nA

## ON

$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$	$I_D = 1 \text{ mA}$	2.1		4	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}$	$I_D = 2.5 \text{ A}$			1.5	$\Omega$

## DYNAMIC

$g_{fs}$	Forward transconductance	$V_{DS} = 25 \text{ V}$	$I_D = 2.5 \text{ A}$	1.5			mho
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V}$ $V_{GS} = 0$	$f = 1 \text{ MHz}$			2000 170 70	pF pF pF

## SWITCHING

$t_d(\text{on})$ $t_r$ $t_d(\text{off})$ $t_f$	Turn-on time Rise time Turn-off delay time Fall time	$V_{DD} = 30 \text{ V}$ $R_{GS} = 50 \Omega$	$I_D = 2.6 \text{ A}$ $V_{GS} = 10 \text{ V}$			45 60 140 65	ns ns ns ns
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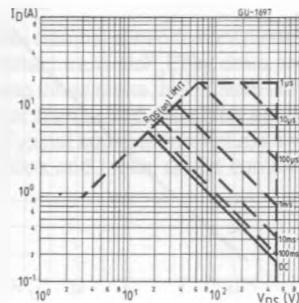
## ELECTRICAL CHARACTERISTICS (Continued)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
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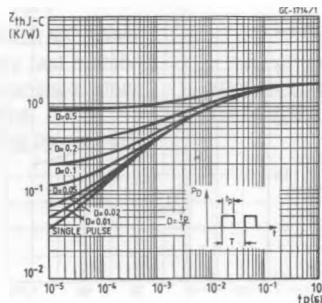
## SOURCE DRAIN DIODE

$I_{SD}$ $I_{SDM}$	Source-drain current Source-drain current (pulsed)	$T_c = 25^\circ\text{C}$		4.5 18	A A
$V_{SD}$	Forward on voltage	$I_{SD} = 9 \text{ A}$ $V_{GS} = 0$		1.5	V
$t_{rr}$	Reverve recovery time		1200		ns
$Q_{rr}$	Reverse recovered charge	$I_{SD} = 4.5 \text{ A}$ $di/dt = 100 \text{ A}/\mu\text{s}$	6		$\mu\text{C}$

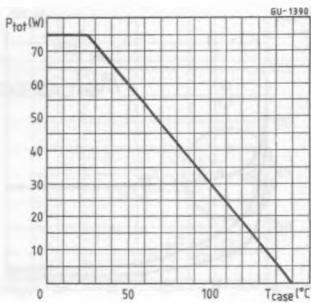
Safe operating areas



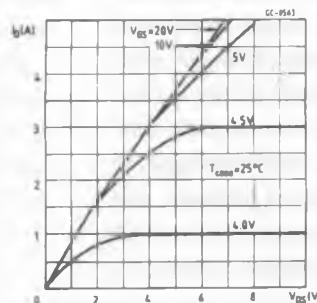
Thermal impedance



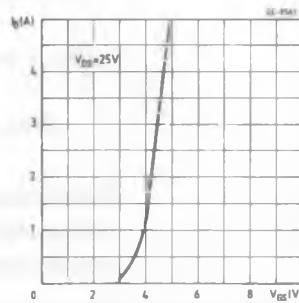
Derating curve



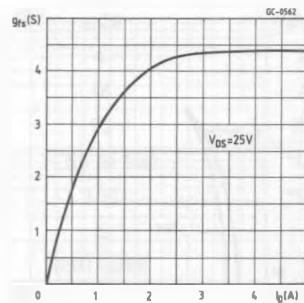
Output characteristics



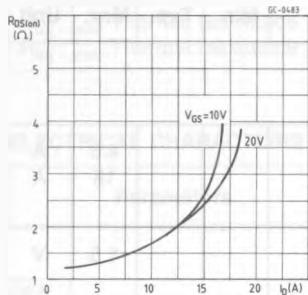
Transfer characteristics



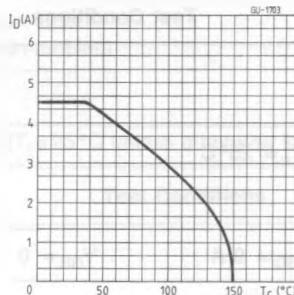
Transconductance



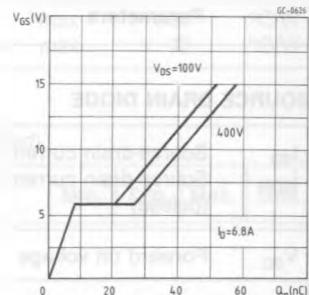
Static drain-source on resistance



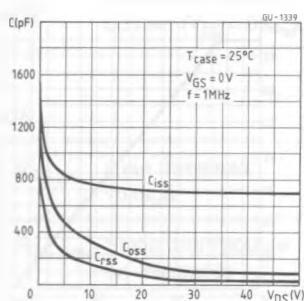
Maximum drain current vs temperature



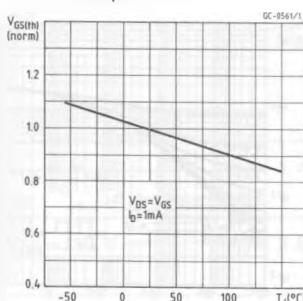
Gate charge vs gate-source voltage



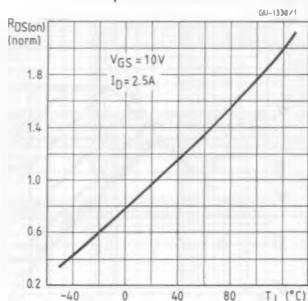
Capacitance variation



Gate threshold voltage vs temperature



Drain-source on resistance vs temperature



Source-drain diode forward characteristics

